

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

E 1075.1253

Sheet 1 of 1
APPLICATION NO.

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FIRST NAMED INVENTOR

10/785,118

INFORMATION DISCLOSURE STATEMENT

Osamu KIMURA, et al.

GROUP ART UNIT

(Use several sheets if necessary)

February 25, 2004

2186

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
<i>(1)</i>	AA	5,937,174	8/10/1999	Weber	395	309	6/28/1996
67	AB	2003/015899	8/21/2003	Hauck et al.	711	113	2/21/2002
(1)	AC	2004/0117579	6/17/2004	Wu et al.	711	170	12/13/2002
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

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		DOCUMENT NO.	DATE	COUNTRY	TRANSLATION YES NO		ABSTRACT			
	AG									
	АН									
	Al									
	AJ									
	AK									
	AL									

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)				NO
	AM	Copy of European Search Report for EP Patent Application No. 04257279.2, dated July 6, 2005.		

EXAMINER	DATE CONSIDERED	
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15	3/7/06	_

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTORNEY DOCKET NO. 1075.1253	APPLICATION NO.
FIRST NAMED INVENTOR Osamu KIMURA, et al.	
FILING DATE	GROUP ART UNIT

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LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

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EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
1	AA	5,819,054	10/6/98	Ninomiya, et al.	395	308	3/17/97
2	AB	6,012,119	1/4/00	Ninomiya, et al.	710	128	1/26/98
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		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES	NO
6	AE	HEI 7-160432	6/23/95	Japan			Abstract and translation of [0001] to [0009] in Detailed Description of the Invention	
6)	AF	HEI 5-189314	7/30/93	Japan			Abstract and translation of [0001] to [0019] in Detailed Description of the Invention	
	AG	HEI 7-20994	1/24/95	Japan				x
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OTHER REFERENCES (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

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